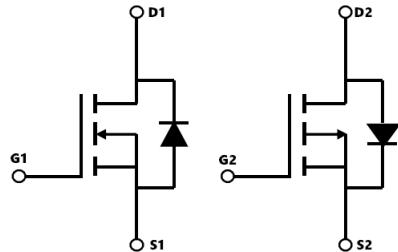


**30V N+P-Channel Enhancement Mode MOSFET****Description**

The AO4606 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

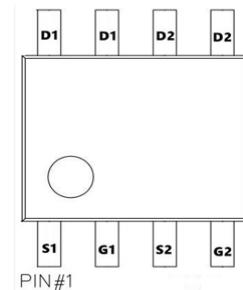
**General Features**

$V_{DS} = 30V$   $I_D = 6A$

$R_{DS(ON)} < 28m\Omega$  @  $V_{GS}=10V$      $R_{DS(ON)} < 42m\Omega$  @  $V_{GS}=4.5V$

$V_{DS} = -30V$   $I_D = -7.6A$

$R_{DS(ON)} < 32m\Omega$  @  $V_{GS}=10V$      $R_{DS(ON)} < 40m\Omega$  @  $V_{GS}=4.5V$

**Absolute Maximum Ratings ( $T_c=25^\circ C$  unless otherwise noted)**

Symbol	Parameter	Rating		Units
		N-Ch	P-Ch	
VDS	Drain-Source Voltage	30	-30	V
VGS	Gate-Source Voltage	$\pm 20$	$\pm 20$	V
$I_D@T_c=25^\circ C$	Continuous Drain Current, $V_{GS}$ @ 10V <sup>1</sup>	6	-7.6	A
$I_D@T_c=100^\circ C$	Continuous Drain Current, $V_{GS}$ @ 10V <sup>1</sup>	4.5	-5.9	A
IDM	Pulsed Drain Current <sup>2</sup>	20	-15	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	22	45	mJ
IAS	Avalanche Current	21	-30	A
$P_D@T_c=25^\circ C$	Total Power Dissipation <sup>4</sup>	2.0	2.0	W
TSTG	Storage Temperature Range	-55 to 150	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	---	62	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	---	5	°C/W

## 30V N+P-Channel Enhancement Mode MOSFET

N-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_D=250\mu\text{A}$	30	---	---	V
$\frac{\partial \text{BV}_{\text{DSS}}}{\partial T_J}$	BVDSS Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$	---	0.023	---	$\text{V}/^\circ\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}$ , $I_D=10\text{A}$	---	19	28	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$ , $I_D=5\text{A}$	---	28	42	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}$ , $I_D=250\mu\text{A}$	1.0	1.7	2.5	V
$\frac{\partial V_{\text{GS(th)}}}{\partial T_J}$	$V_{\text{GS(th)}}$ Temperature Coefficient		---	-5.2	---	$\text{mV}/^\circ\text{C}$
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=24\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $T_J=25^\circ\text{C}$	---	---	1	$\text{uA}$
		$V_{\text{DS}}=24\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $T_J=55^\circ\text{C}$	---	---	5	
$I_{\text{GSS}}$	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$ , $V_{\text{DS}}=0\text{V}$	---	---	$\pm 100$	nA
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=5\text{V}$ , $I_D=10\text{A}$	---	16	---	S
$R_g$	Gate Resistance	$V_{\text{DS}}=0\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	2.5	5	$\Omega$
$Q_g$	Total Gate Charge (4.5V)	$V_{\text{DS}}=20\text{V}$ , $V_{\text{GS}}=4.5\text{V}$ , $I_D=10\text{A}$	---	7.2	---	$\text{nC}$
$Q_{\text{gs}}$	Gate-Source Charge		---	1.4	---	
$Q_{\text{gd}}$	Gate-Drain Charge		---	2.2	---	
$T_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}}=15\text{V}$ , $V_{\text{GS}}=10\text{V}$ , $R_G=3.3$ , $I_D=5\text{A}$	---	4.1	---	$\text{ns}$
$T_r$	Rise Time		---	9.8	---	
$T_{\text{d(off)}}$	Turn-Off Delay Time		---	15.5	---	
$T_f$	Fall Time		---	6.0	---	
$C_{\text{iss}}$	Input Capacitance	$V_{\text{DS}}=15\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	572	---	$\text{pF}$
$C_{\text{oss}}$	Output Capacitance		---	81	---	
$C_{\text{rss}}$	Reverse Transfer Capacitance		---	65	---	
$I_s$	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0\text{V}$ , Force Current	---	---	10	A
$I_{\text{SM}}$	Pulsed Source Current <sup>2,5</sup>		---	---	20	A
$V_{\text{SD}}$	Diode Forward Voltage <sup>2</sup>	$V_{\text{GS}}=0\text{V}$ , $I_s=1\text{A}$ , $T_J=25^\circ\text{C}$	---	---	1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is  $V_{\text{DD}}=25\text{V}$ ,  $V_{\text{GS}}=10\text{V}$ ,  $L=0.1\text{mH}$ ,  $I_{\text{AS}}=21\text{A}$
- 4 .The power dissipation is limited by  $150^\circ\text{C}$  junction temperature
- 5.The data is theoretically the same as  $I_D$  and  $I_{\text{DM}}$  , in real applications , should be limited by total power dissipation.

## 30V N+P-Channel Enhancement Mode MOSFET

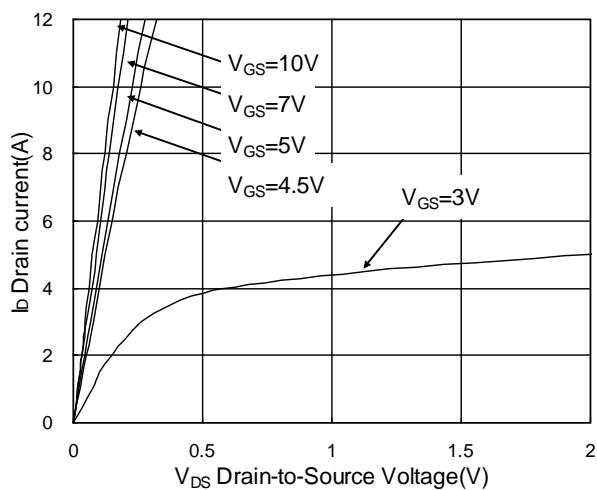
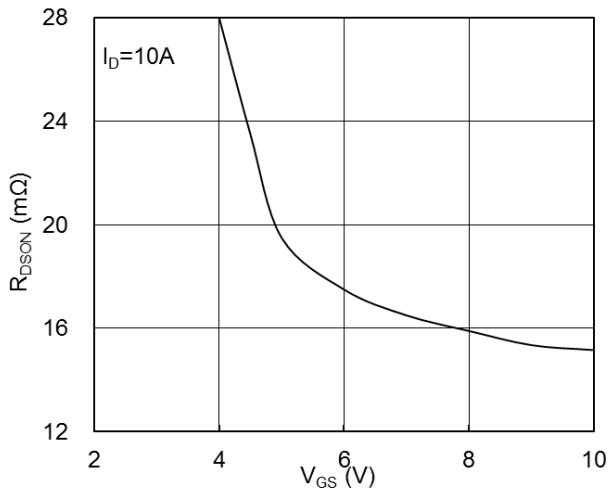
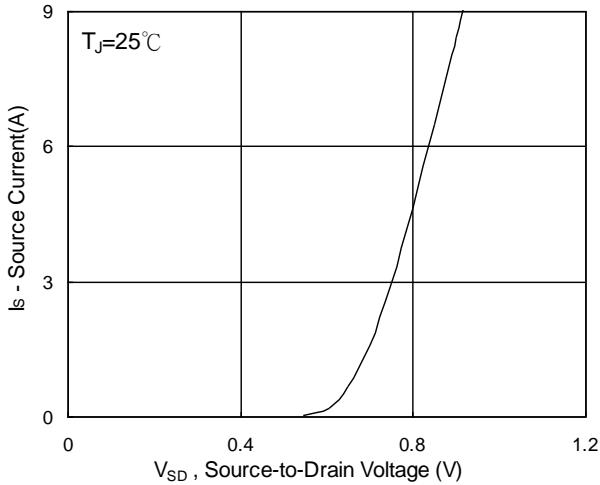
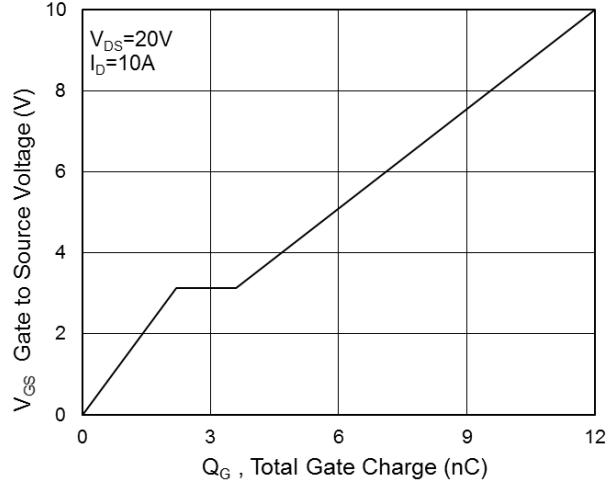
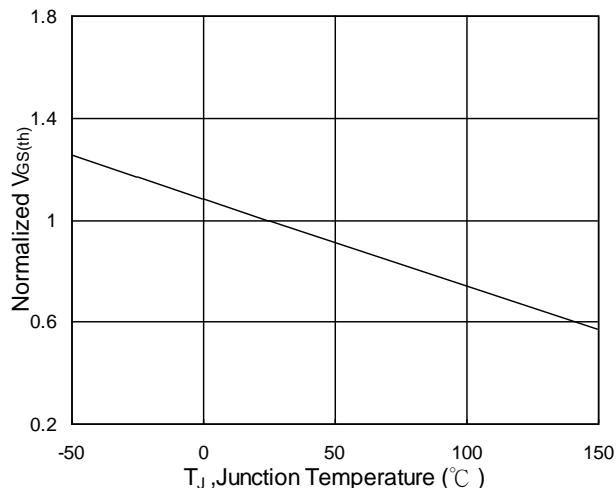
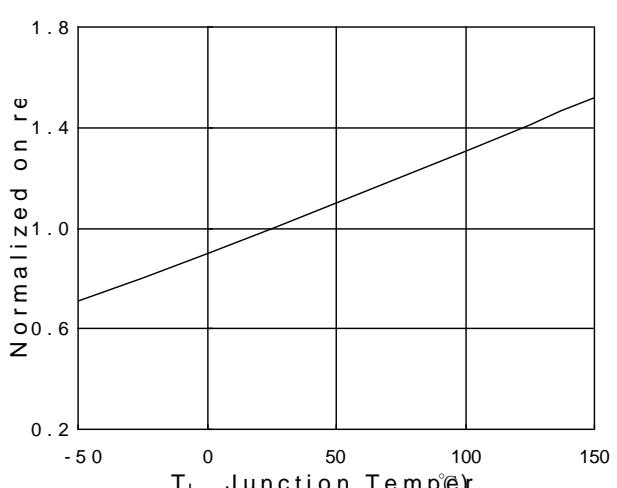
P-Channel Electrical Characteristics ( $T_J=25^\circ C$ , unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-30	---	---	V
$\frac{\partial BV_{DSS}}{\partial T_J}$	$BV_{DSS}$ Temperature Coefficient	Reference to $25^\circ C, I_D=-1mA$	---	-0.021	---	$V/^\circ C$
$R_{DS(ON)}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=-10V, I_D=-7A$	---	24	32	$m\Omega$
		$V_{GS}=-4.5V, I_D=-5A$	---	32	40	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=-250\mu A$	-1.0	-1.6	-2.5	V
$\frac{\partial V_{GS(th)}}{\partial T_J}$	$V_{GS(th)}$ Temperature Coefficient		---	-4.2	---	$mV/^\circ C$
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=-24V, V_{GS}=0V, T_J=25^\circ C$	---	---	1	$\mu A$
		$V_{DS}=-24V, V_{GS}=0V, T_J=55^\circ C$	---	---	5	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	$\pm 100$	nA
$g_{fs}$	Forward Transconductance	$V_{DS}=-5V, I_D=-7A$	---	15	---	S
$R_g$	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$		15	30	
$Q_g$	Total Gate Charge (-4.5V)	$V_{DS}=-20V, V_{GS}=-4.5V, I_D=-7A$	---	9.8	---	$nC$
$Q_{gs}$	Gate-Source Charge		---	2.2	---	
$Q_{gd}$	Gate-Drain Charge		---	3.4	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=-15V, V_{GS}=-10V, R_G=3.3, I_D=-5A$	---	16.4	---	$ns$
$T_r$	Rise Time		---	20.2	---	
$T_{d(off)}$	Turn-Off Delay Time		---	55	---	
$T_f$	Fall Time		---	10	---	
$C_{iss}$	Input Capacitance	$V_{DS}=-15V, V_{GS}=0V, f=1MHz$	---	930	---	$pF$
$C_{oss}$	Output Capacitance		---	148	---	
$C_{rss}$	Reverse Transfer Capacitance		---	115	---	
$I_s$	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0V, \text{Force Current}$	---	---	-7.6	A
$I_{SM}$	Pulsed Source Current <sup>2,5</sup>		---	---	-15	A
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0V, I_S=-1A, T_J=25^\circ C$	---	---	-1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZcopper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3.The EAS data sh.The power dissipation is limited by ows Max. rating
4. The test condition is  $V_{150^\circ C}$  junction temperature $=-25 V, V_{GS}=-10V, L=0.1mH, I_{AS}=-30A$
- 5 .The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

## 30V N+P-Channel Enhancement Mode MOSFET

**N-Channel Typical Characteristics****Fig.1 Typical Output Characteristics****Fig.2 On-Resistance vs Gate-Source Voltage****Fig.3 Forward Characteristics of Reverse****Fig.4 Gate-Charge characteristics****Fig.5 Normalized  $V_{GS(th)}$  vs  $T_J$** **Fig.6 Normalized  $R_{DS(on)}$  vs  $T_J$**

30V N+P-Channel Enhancement Mode MOSFET

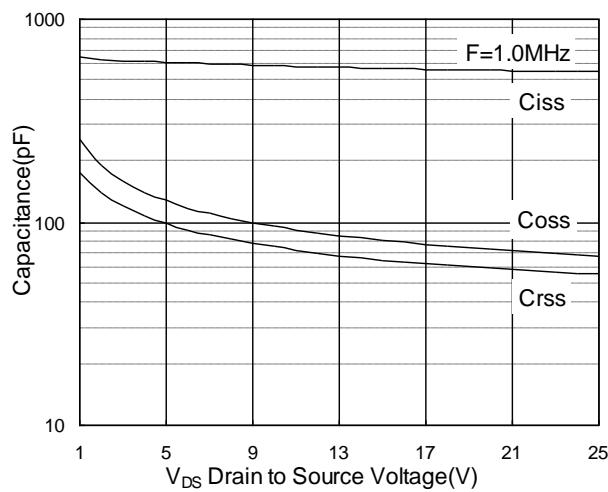


Fig.7 Capacitance

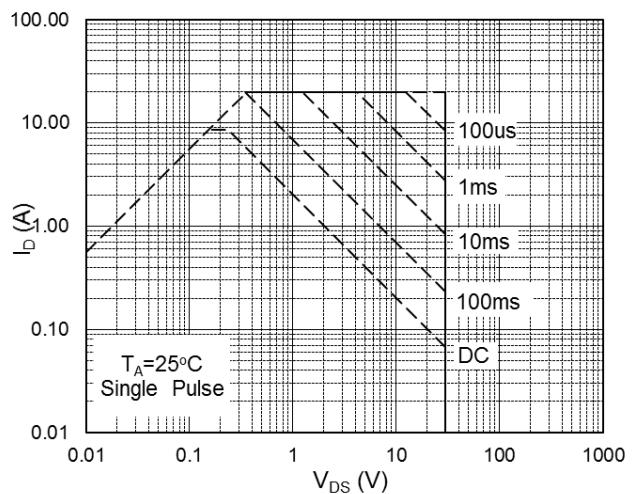


Fig.8 Safe Operating Area

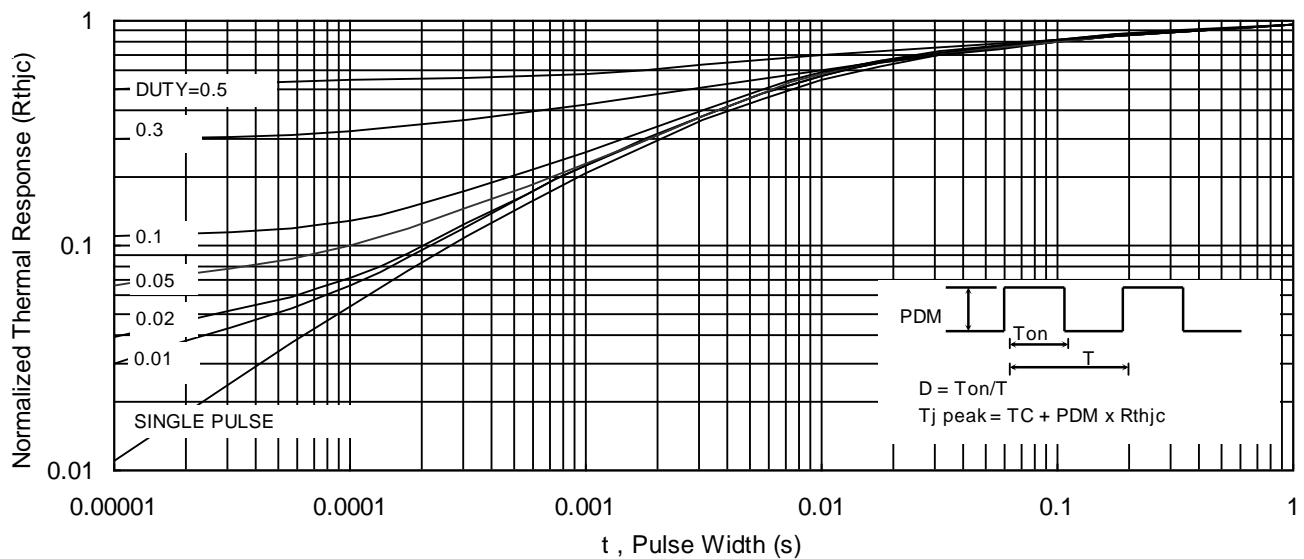


Fig.9 Normalized Maximum Transient Thermal Impedance

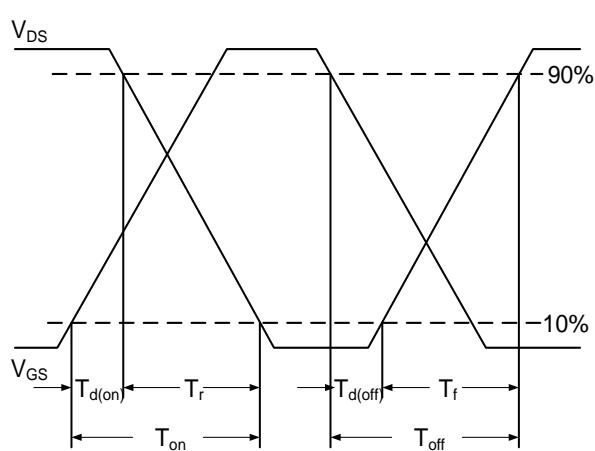


Fig.10 Switching Time Waveform

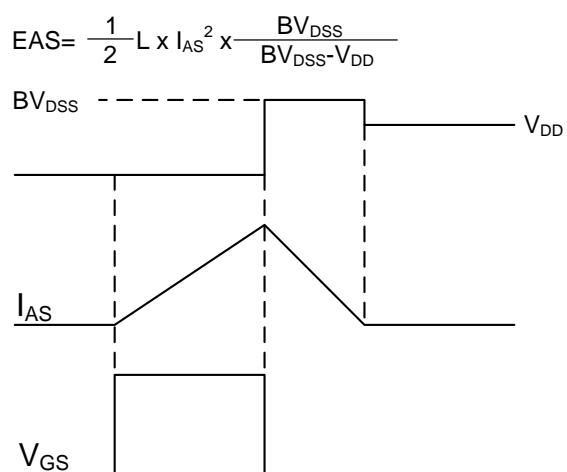
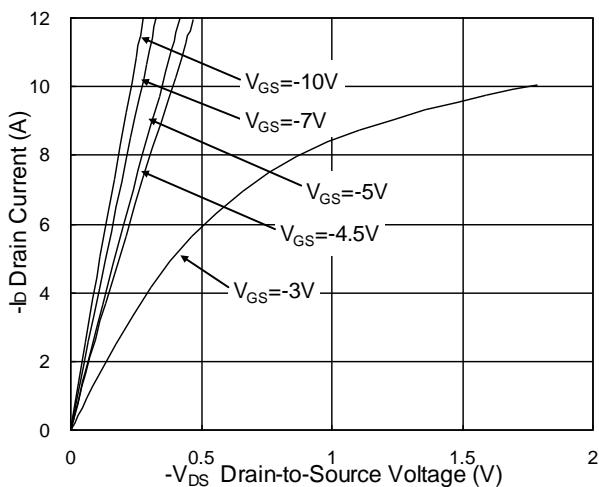
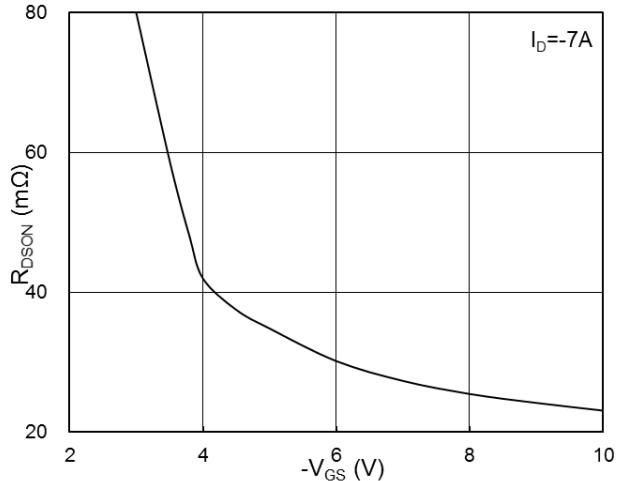


Fig.11 Unclamped Inductive Waveform

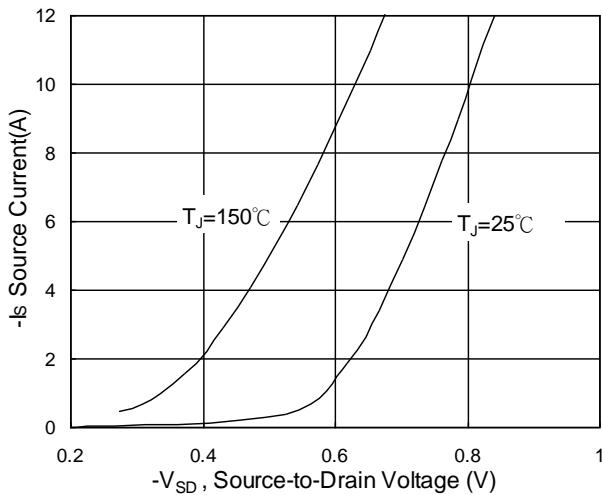
**P-Channel Typical Characteristics**



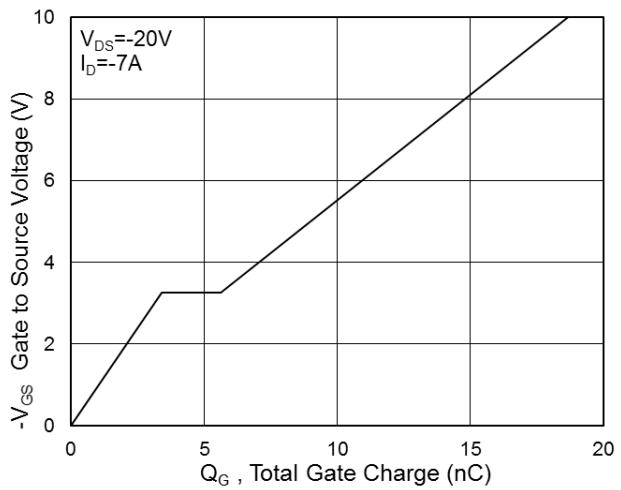
**Fig.1 Typical Output Characteristics**



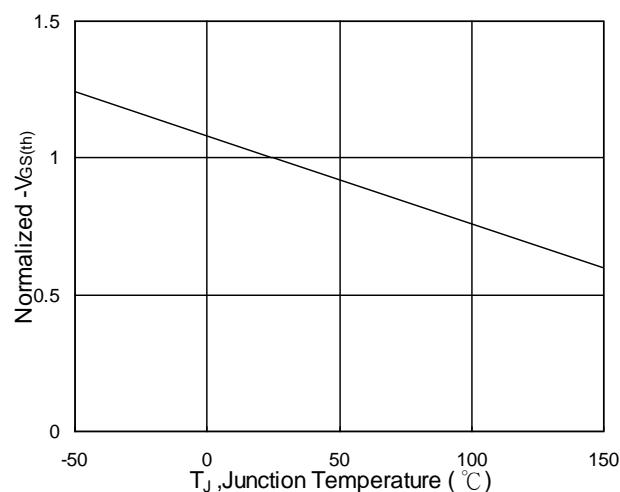
**Fig.2 On-Resistance vs Gate-Source Voltage**



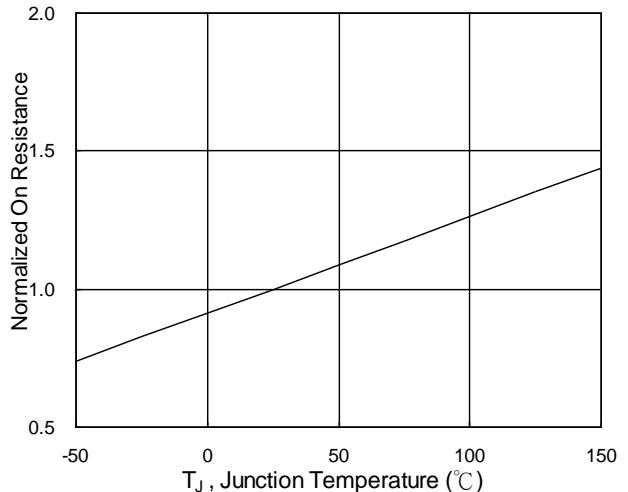
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**

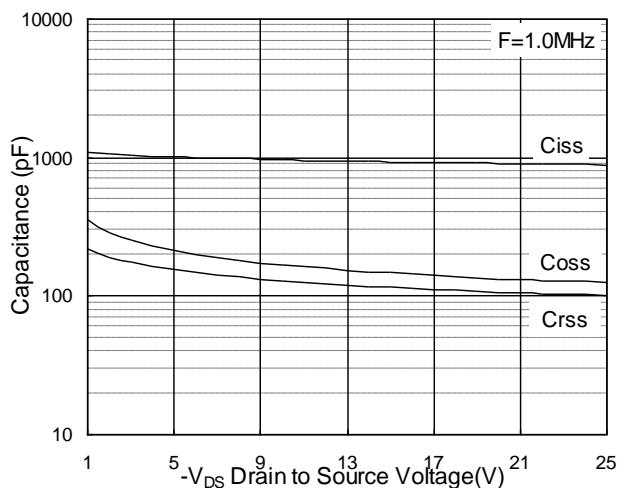


**Fig.5 Normalized  $V_{GS(th)}$  vs  $T_J$**

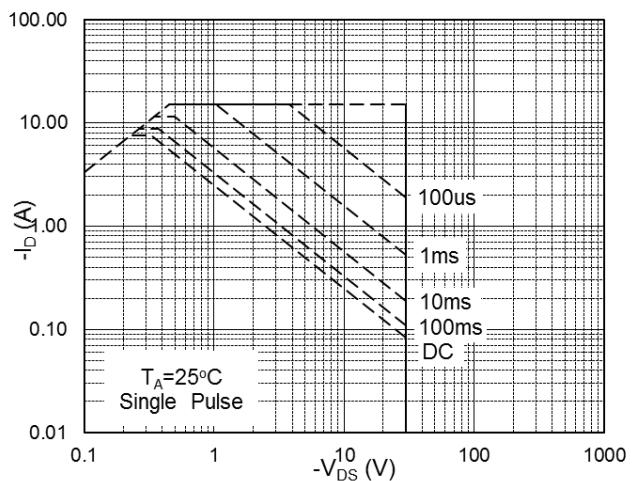


**Fig.6 Normalized  $R_{DS(on)}$  vs  $T_J$**

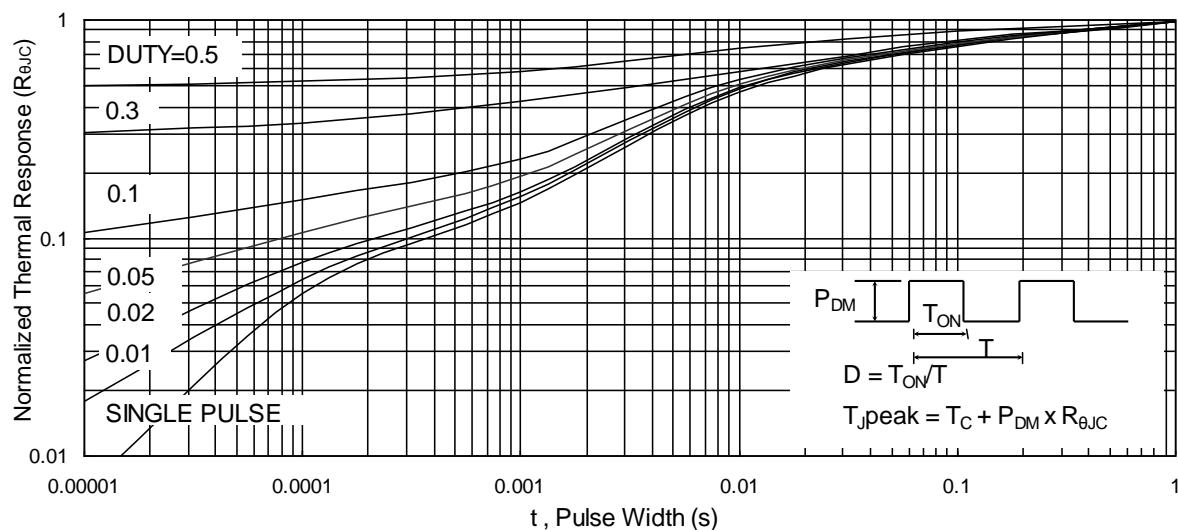
**30V N+P-Channel Enhancement Mode MOSFET**



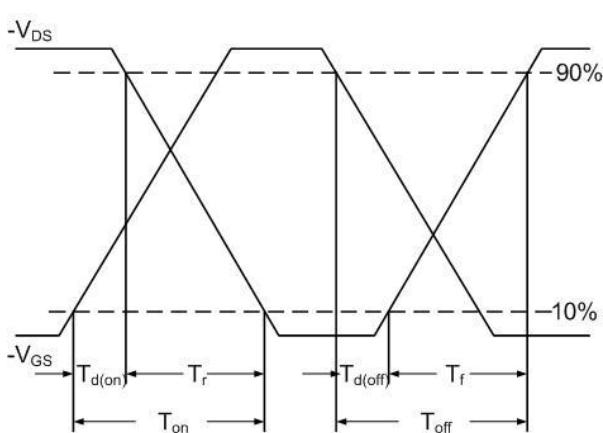
**Fig.7 Capacitance**



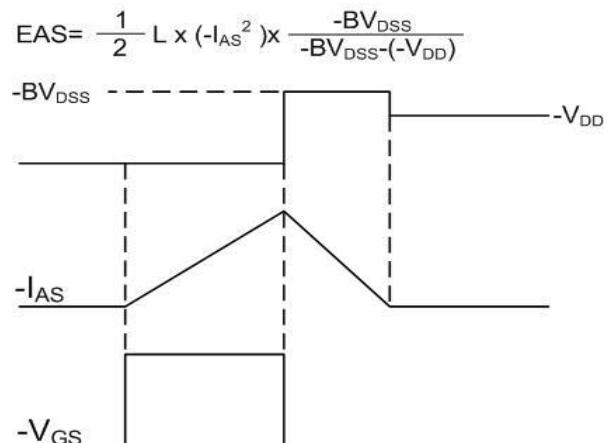
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

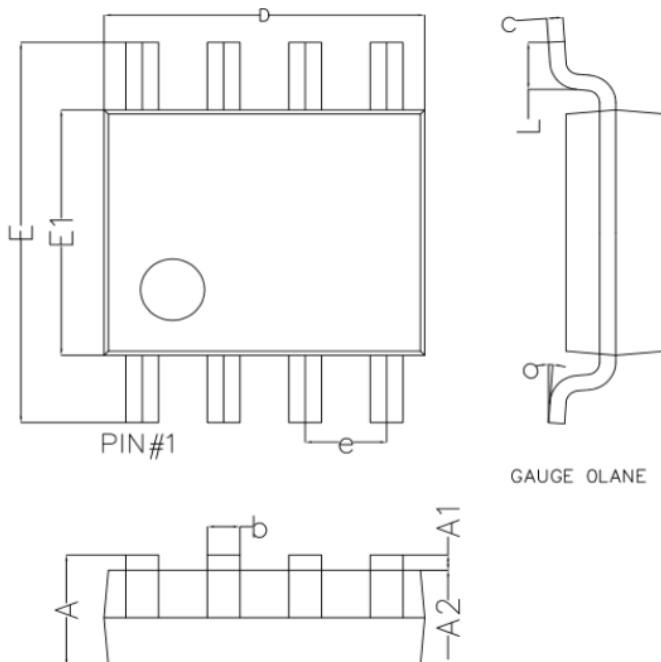


**Fig.10 Switching Time Waveform**



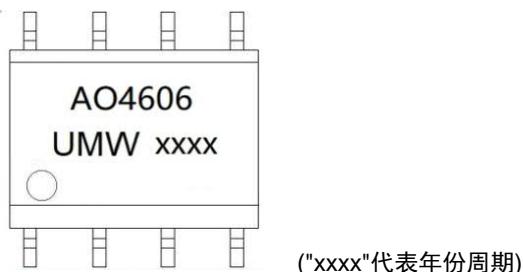
**Fig.11 Unclamped Inductive Waveform**

## Package Mechanical Data-SOP-8



Symbol	Dim in mm		
	Min	Nor	Max
A	1.350	1.550	1.750
A1	0.100	0.175	0.250
A2	1.350	1.450	1.550
b	0.330	0.420	0.510
c	0.170	0.210	0.250
D	4.800	4.900	5.000
e	1.270 (BSC)		
E	5.800	6.000	6.200
E1	3.800	3.900	4.000
L	0.400	0.835	1.2700
o	0°	4°	8°

## Marking



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[PJMF600N65E1\\_T0\\_00201](#) [PJMF900N65E1\\_T0\\_00201](#) [PJMF900N60E1\\_T0\\_00201](#)